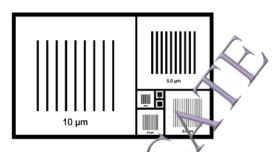


## AISthesis Products, Inc.

Advanced Imaging Products for Nanotechnology, Engineering and Life Sciences

## Wafer Level Certificate of Traceability for Pelcotec™ Critical Dimension Standard





NIST Cartified CD/Pagalibration | Pagalution | Pagalution

Product Number: Pelcotec™ 683-01 CDMS-0.1T

<u>Product Description:</u> 2.5x2.5mm **Pelcotec<sup>™</sup>** 2mm-100nm Critical Dimension Magnification Standard

Wafer Identifier: CD-XE01

Manufactured for and distributed by:

PELLA\_INC

Micro copy Products for Science and Industry

The accuracy of these products was determined by reference comparison to working standards traceable to the National Institute of Standards and Technology (NIST), Test No. 861/280822-11.

Line	Average pitch of wafer	Number of lines averaged	A 'erage oitch un formity (1σ uncertainty)	Total expanded uncertainty (3σ) average pitch for wafer*
2.0mm	2.00 mm	2	+ 2µm (±0.10%)	± 7µm (±0.35%)
1.0mm	1.00 mm	2	± (±0.10%)	± 3.5µm (±0.35%)
0.5mm	0.500 mm	2	± 0.5µm (±0.10%)	± 1.75µm (±0.35%)
0.25mm	0.250 mm	2	. 0.25µm (±0.10%)	± 0.9µm (±0.35%)
10µm	10.00 μm	9	± 0.01µm (±0.10%)	± 0.035µm (±0.35%)
5µm	5.00 µm	12	± 0.01µm (±0.20%)	± 0.035µm (±0.70%)
2µm	2.00 µm	160	± 0.004µm (±0.20%)	± 0.014µm (±0.70%)
1µm	1.00 µm	77	± 0.002µm (±0.20%)	± 0.007µm (±0.70%)
500nm	500.8 nm	20	± 1.00nm (±0.20%)	± 3.5nm (±0.70%)
250nm	250.7 nm	2	± 0.50nm (±0.20%)	± 1.75nm (±0.70%)
100nm	100.3 nm	52	± 0.20nm (±0.20%)	± 0.75nm (±0.70%)

<sup>\*</sup> The 3σ uncertainty (95% combance interval) average pitch is determined using a minimum of nine die per production wafer. Each average pitch is determined using 100+ measurements on each die averaged over the stated number of lines. The total expanded uncertainty includes both Type A and Type B uncertainties corrected for sample size using an appropriate Student t-factor.

Equipment used:

Instrument Medal number

nstrument	Model number	Seriai #	NIST Certified CD/Recalibration	Resolution	Repeatability
E-SEM	FEI Verios	9922551	CD-PG01-0211/June 2018	0.9nm	0.03%
		•			
				·	
Certified by		Signature		Date	
Certified by		Signature	<del></del>	Date	

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